

SEARCHED

Class	Sub.	Date	Exmr.
530	399	8/6/01	SLW
536	23.51		
435	35		
536	23.1		
435	320.1		
435	325		
435	252.3		
updated		10/22/02	SLW
530	300		
	324		
	388.22		
	326		
424	85.1		
	198.1		
	1.11		
514	2		

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INTERFERENCE SEARCHED

Class	Sub.	Date	Exmr.
Interfer.		1/29/02	SLW
STIC databases		SEQ ID NO: 2, 5	
Interference		10/17/02	SLW
STIC databases			
SEQ ID NO: 2			
530	300	10/18/02	SLW
	324		
	399		
424	85.1		
	198.1		
514	2		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	Date	Exmr.
SEQ ID #1 with Xaa ₀ (enclosed) Issued - Patents, NIA, GenEmble, N-Geneset-36, EST, BLAST alignment SEQ ID NO: 1	8/6/01	SLW
Inventors, PALM, EAST	8/7/01	SLW
Text Search SEQ ID NO: 1 USPAT, EPO, Derwent, Biosis	8/8/01	SLW
Interference STIC - Search SEQ ID NO: 2 SEQ ID NO: 5	1/29/02	SLW
updated SEQ ID NO: 1, 2 w/visual inspection of residue 1, 18	2/3/02	SLW
updated Interference STIC - SEQ ID NO: 2	3/30/02	SLW
	10/18/02	SLW
	10/17/02	SLW